Electronic Supporting Information

Growth and Characterization of Zeolitic Imidazolate Framework-8 Nanocrystalline Layers on Microstructured Surfaces for Liquid Crystal Alignment

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function signal generator
/oscilloscope AC amplifier

computer

silicon detector polarizer LC cell polarizer diode laser

Fig. S1 Schematic of the electro-optical experimental set-up used in this work

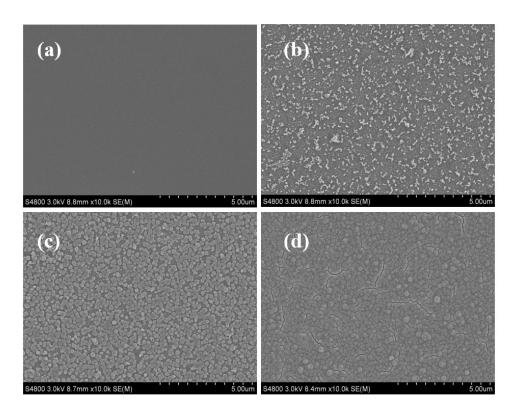


Fig. S2 SEM top views of ZIF-8 layer prepared on pristine sol-gel films (a) after 1 cycle growth of 5 min (b), 10 min (c), and 30 min (d)

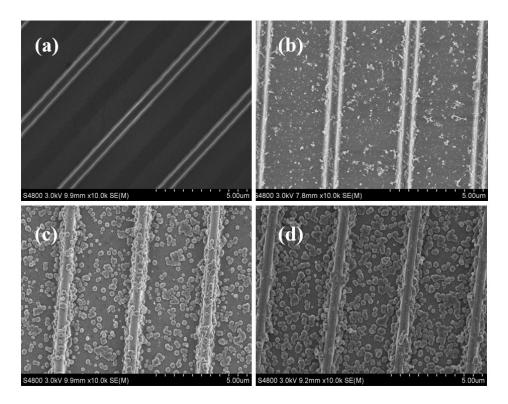


Fig. S3 SEM top views of ZIF-8 layer prepared on patterned sol-gel films with grating periods (Λ) of 3.9 μ m (a) after 1 cycle growth of 10 min (b), 30 min (c) and 60 min (d)